

Search Notes



Application/Control No.

10/685,560

Examiner

Sam K. Ahn

Applicant(s)/Patent under Reexamination

CHOU ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	229, 230, 232 233, 346, 348 350, 354, 355 364, 373	12/26	am
370	516, 518, 519 520		
379	340, 398		
455	63.1, 114.2 296		
708	323	2/4	am

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
FAST - inventor search keyword and citation search IEEE and google keyword and citation search	12/26 2/4	am am
consulted Young Tse 375 P.E.	2/4	am